

# 5th High Level Expert Meeting 2012 - Asphere Metrology

## Detailed Programme - *preliminary*

(As of February 27<sup>th</sup> 2012)



### Day 1: Tuesday March 6<sup>th</sup> / Morning

Chair: Dr. F. Siewert; Helmholtz-Zentrum Berlin GmbH; Germany

- 10.00 Conference opening and overview;** Prof. Dr. F. Löffler; CC UPOB e.V.; and Dr. M. Schulz; PTB; Germany
- 10.20 Measurement of the aspheres with the Isara 400;** Dr. H.A.M. Spaan; IBS Precision Engineering BV; Netherlands
- 10.50 Test measurements on the Tilted Wave Interferometer;** G. Baer; University Stuttgart ITO; Germany
- 11.20 Coffee break and table top presentations**
- 11.50 3D tactile scanning on aspheric lenses;** Dr. A. Beutler; Mahr GmbH; Germany
- 12.20 Interferometric Measurements of Aspheric and Freeform Surfaces;** D. Pearson; ESDI; USA
- 12.50 Lunch Break**

### Day 1: Tuesday March 6<sup>th</sup> / Afternoon

Chair: G. Schneider; Schneider GmbH & Co. KG; Germany

- 13.50 Asphere and Freeform Measurement by 3-D Profilometer for Ultraprecision Manufacturing;** S. Scheiding / A. Gebhardt; Fraunhofer Institute For Applied Optics And Precision Engineering IOF; Germany
- 14.20 CGH Design and applications in optical testing;** Dr. R. Schreiner; JENOPTIK Laser, Optik, Systeme GmbH;
- 14.50 Analysis of CGH adjustment errors and their minimization;** Dr. T. Ottenstein; DIOPTIC GmbH; Germany
- 15.10 Coffee break and table top presentations**
- 15.40 Specular freeform surfaces measured by Deflectometry;** E. Olesch; University of Erlangen-Nuremberg; Germany
- 16.10 Aspheric Testing in Null Configuration with a Twyman-Green-Interferometer;** Dr. K. Mantel; Max Planck Institut Erlangen; Germany
- 16.40 Asphere and Freeform Metrology at Carl Zeiss;** Dr. T. Köhler; Carl Zeiss Jena GmbH; Germany
- 17.10 Closing**
- 19.00 Conference Dinner**

### Day 2: Wednesday March 7<sup>th</sup> / Morning

Chair: Dr. K. F. Beckstette; Carl-Zeiss Jena GmbH; Germany

- 9.00 Opening**
- 9.05 Licencing opportunities and patending policy of PTB;** Dr. B. Smandek; Technology Transfer Commissioner; PTB; Germany
- 9.20 An alternative solution to non-contact asphere metrology based on MWLI technology;** Dr. G. Berger; Luphos GmbH; Germany
- 9.50 Recent Advances in Aspheric Stitching Interferometry;** J. P. Lormeau; QED Technologies International; USA
- 10.20 Chances and limits of optical in-situ measurements;** I. Hollenbach / Dr. M. Lehnndorff; Kugler GmbH; Germany
- 10.50 Coffee break and table top presentations**
- 11.20 Asphere Metrology round robin result of UA3P;** K. Kubo; Panasonic Production Technology Co., Ltd; UA3P Development Team; Japan
- 11.50 Freeform optics and scanning deflectometric testing of aspheres;** S. Stürwald; Fraunhofer IPT; Germany
- 12.30 Lunch Break**

### Day 2: Wednesday March 7<sup>th</sup> / Afternoon

Chair: J.M. Asfour, DIOPTIC GmbH; Germany

- 13.30 Potentials and Limits of Deflectometry;** Prof. Dr. G. Häusler; University of Erlangen-Nuremberg; Germany
- 14.00 Orthogonal Polynomial Representations for Aspheres and Freeforms;** Dr. A. Kulawiec; QED Technologies International; USA
- 14.30 Coffee break and table top presentations**
- 14.50 Discussion on Comparability;** Dr. S. Quabis; PTB; Germany
- 15.20 Final Discussion / Outlook;**
- 15.50 Summary;** Prof. Dr. F. Löffler; CC UPOB e.V.; Germany
- 16.15 Conference Closing**